

**Search Notes**

Application/Control No.

10/517,454

Examiner

Alan Wong

Applicant(s)/Patent under  
Reexamination

BOUNY, JEAN-JACQUES

Art Unit

2817

**SEARCHED**

Class	Subclass	Date	Examiner
375	397	4/25/2006	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST See Printout	4/28/2006	AW
330/149, 124R 333/26 Text Limited See Printout	4/27/2006	AW